

# SKW 3-6 STI Patterned 300mm Wafer Metrology Plans

## 1. Planarity Measurement Plan

### (1) Step Height Measurement

- a) Basic mode
- b) Diameter mode
- c) Standard mode

### (2) Thickness Measurement

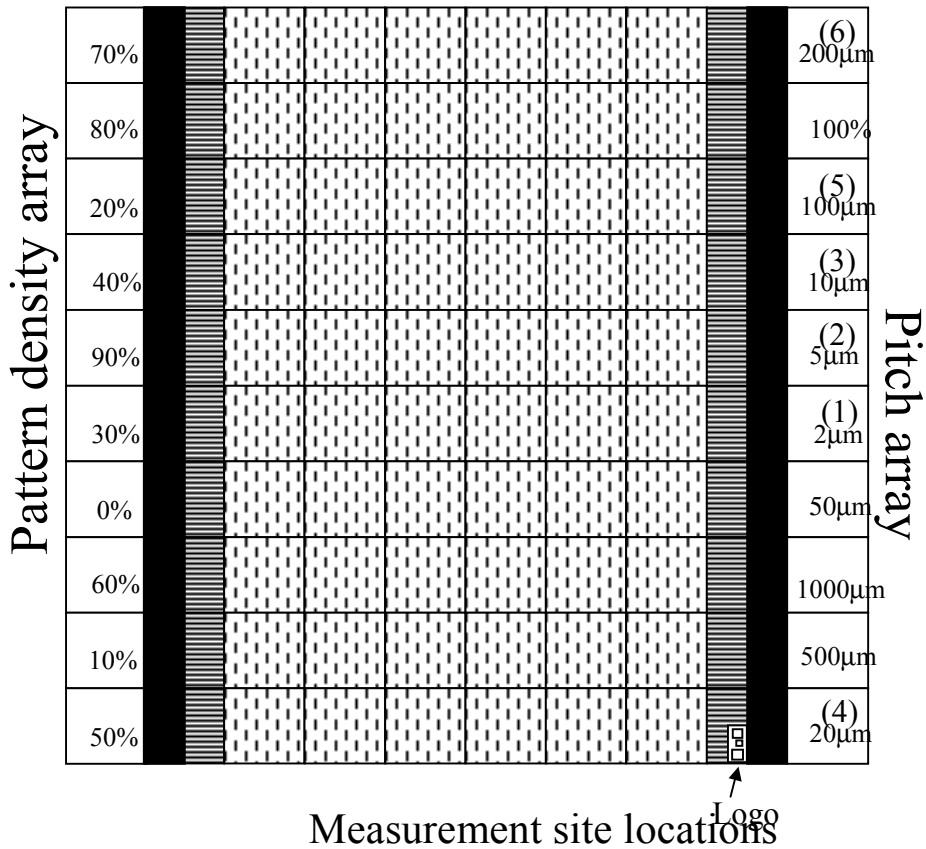
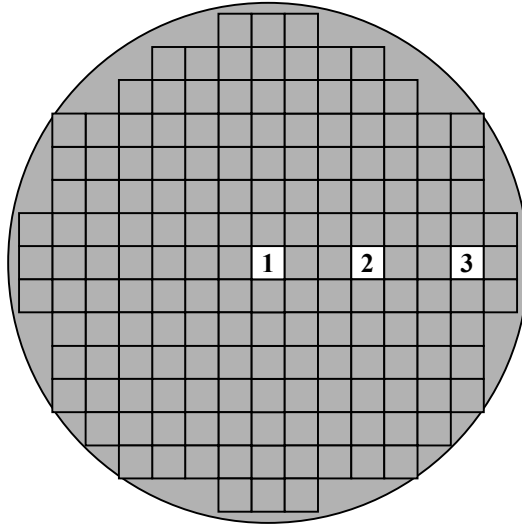
- a) Basic mode
- b) Diameter mode
- c) Standard mode

## 2. Defectivity Measurement Plan

# 1. Planarity Measurement Plan

## (1) Step Height Measurement

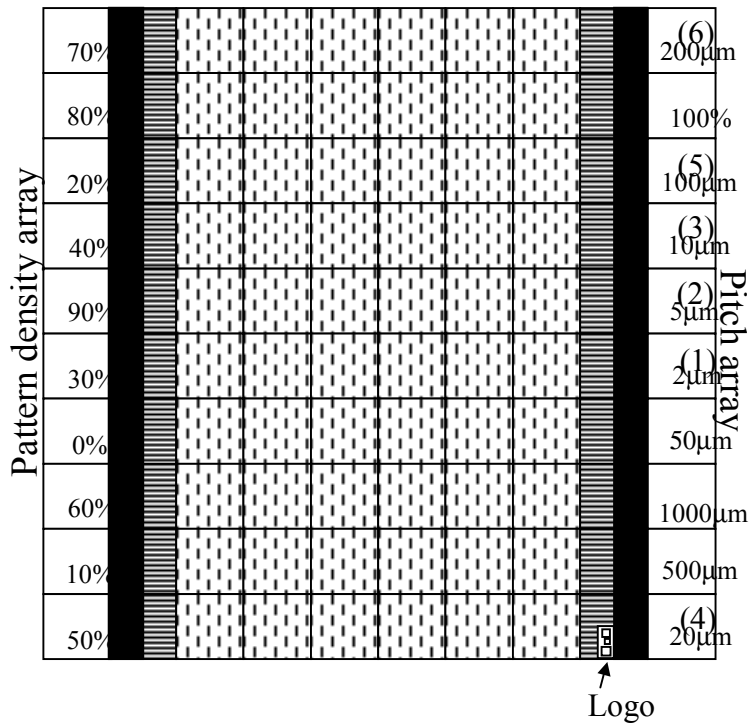
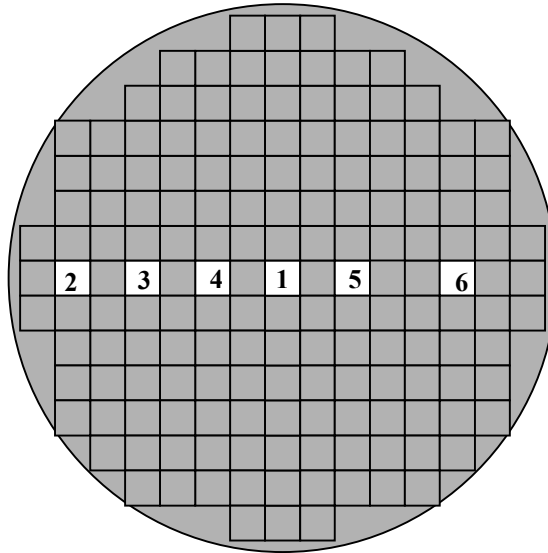
### a) Basic mode



# 1. Planarity Measurement Plan

## (1) Step Height Measurement

### b) Diameter mode

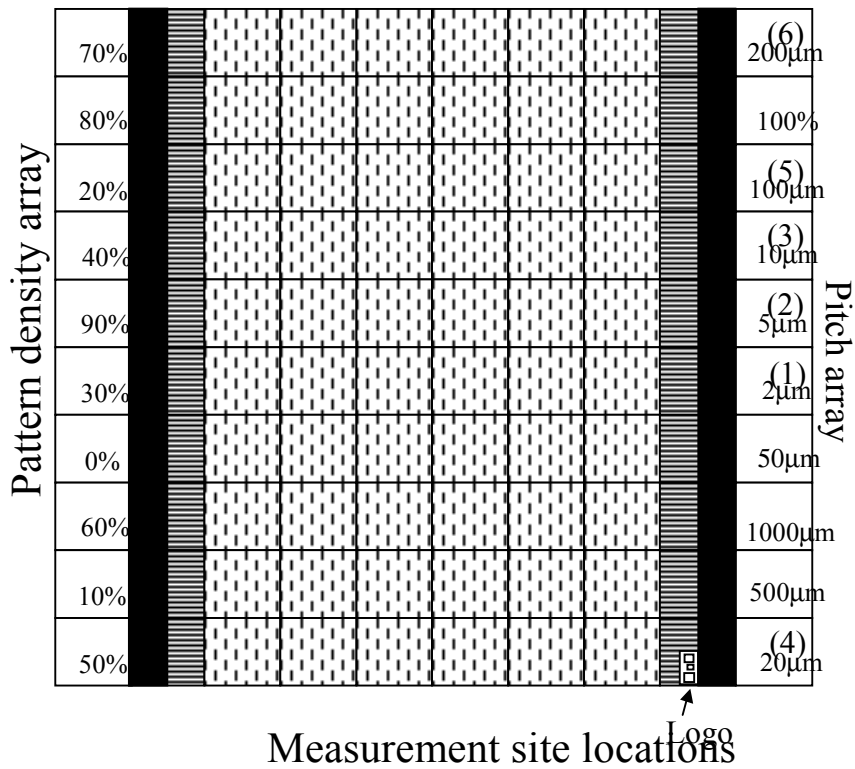
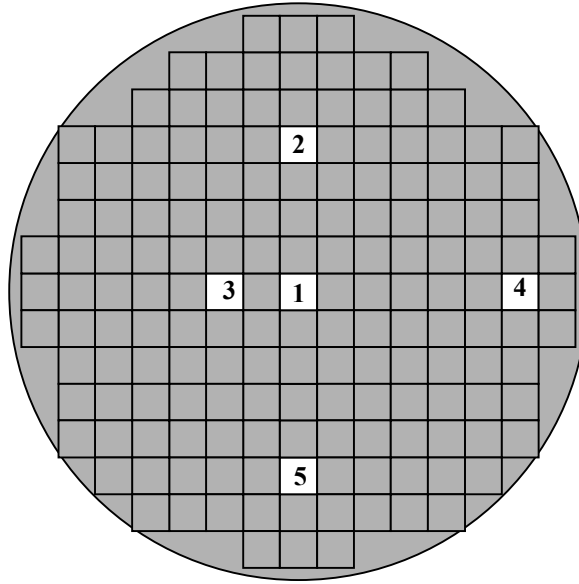


Measurement site locations

# 1. Planarity Measurement Plan

## (1) Step Height Measurement

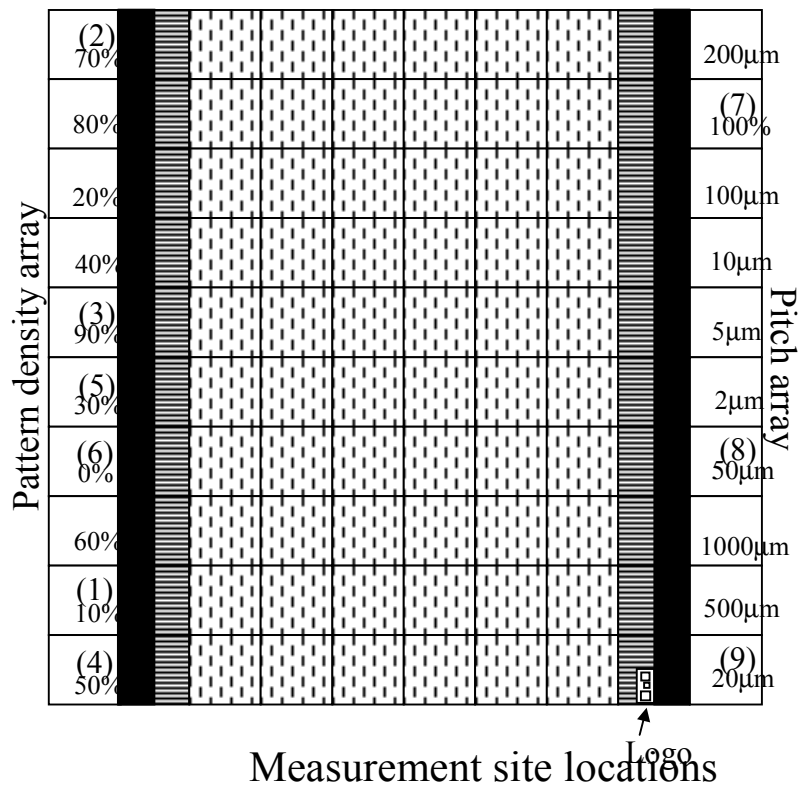
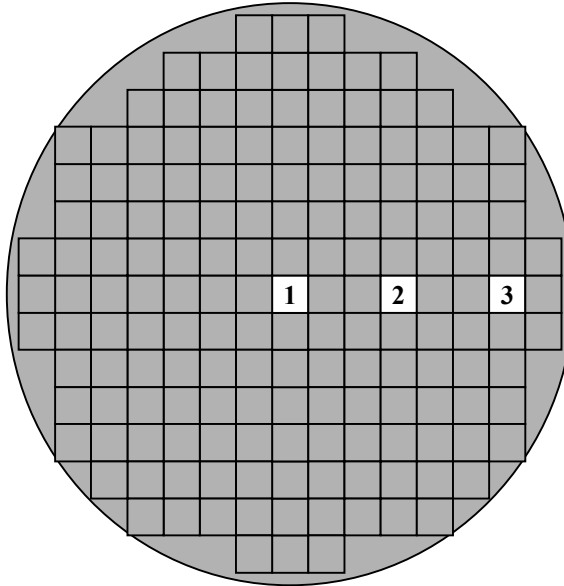
### 3) Standard mode



# 1. Planarity Measurement Plan

## (2) Thickness Measurement

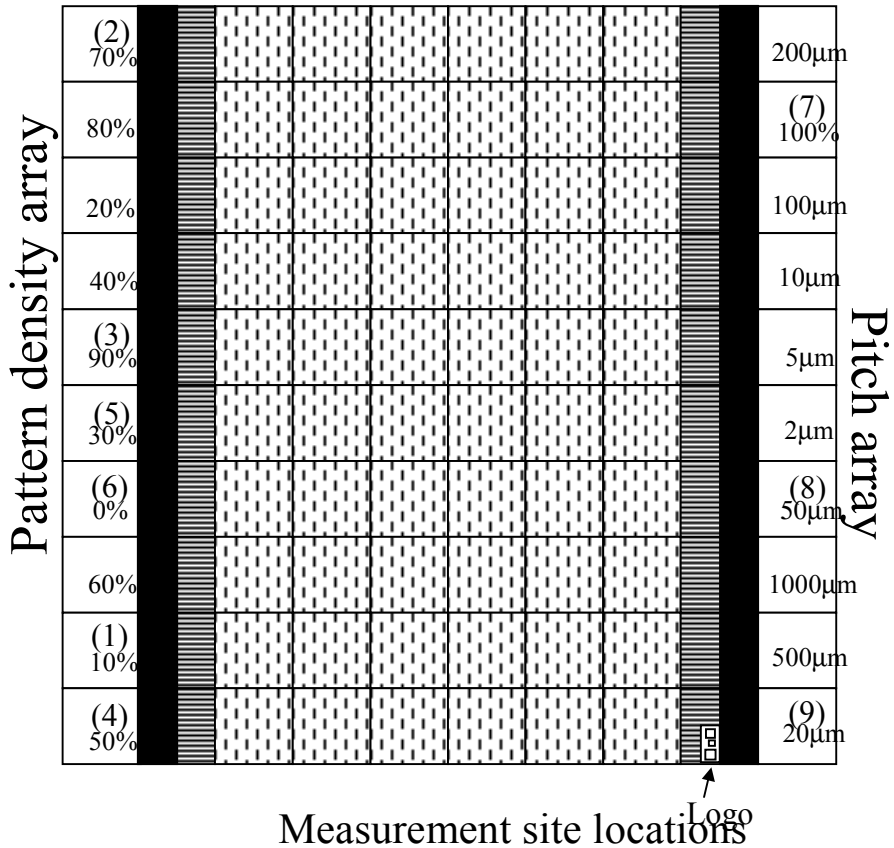
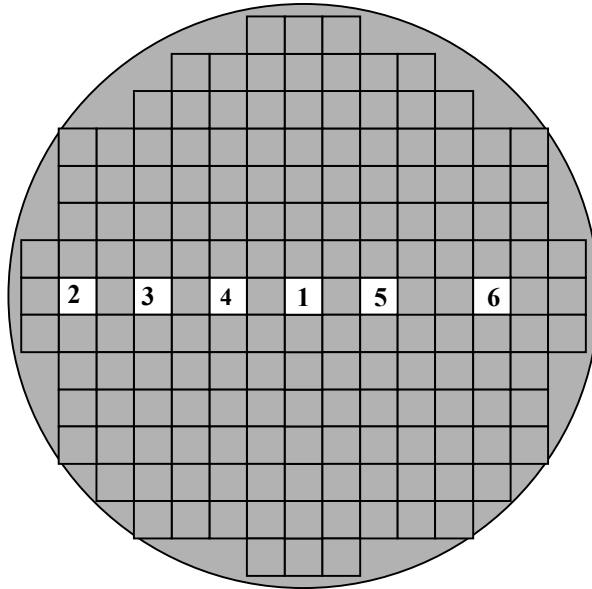
### a) Basic mode



# 1. Planarity Measurement Plan

## (2) Thickness Measurement

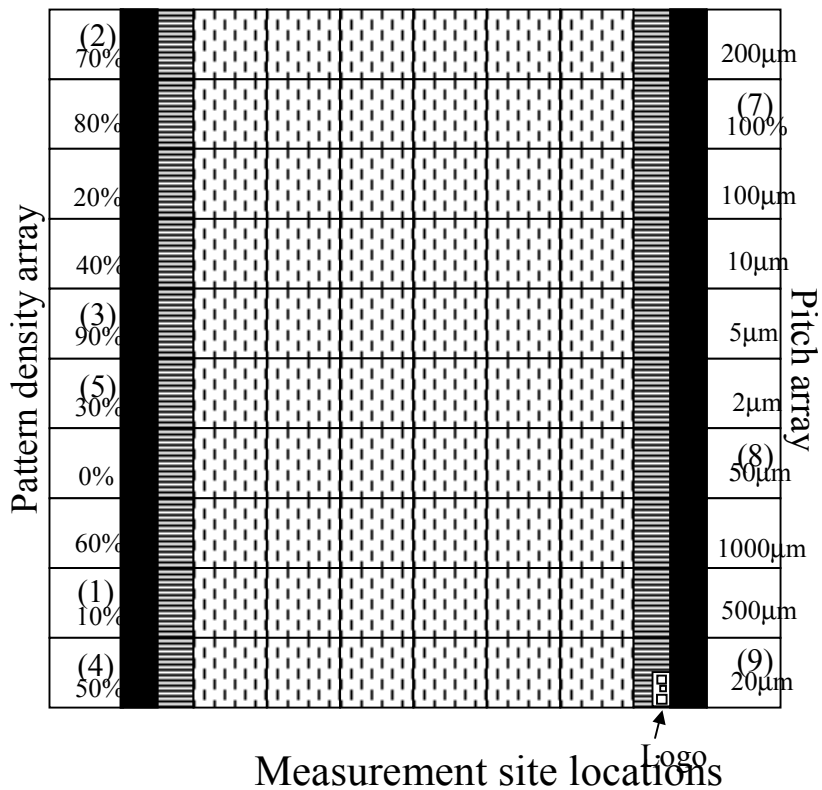
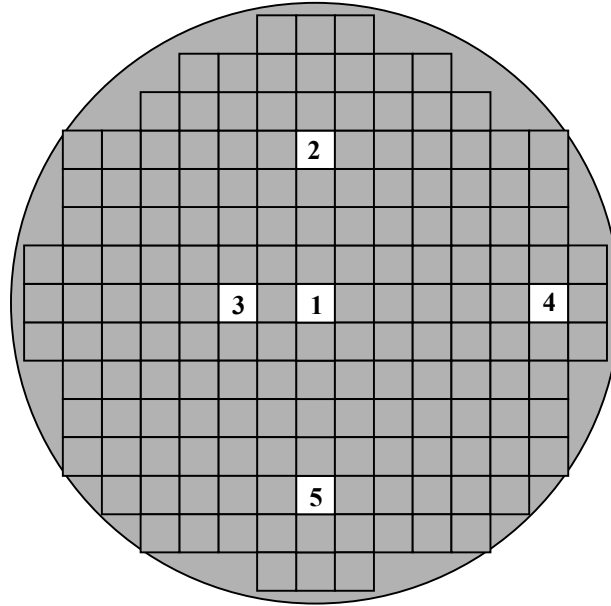
### b) Diameter mode



# 1. Planarity Measurement Plan

## (2) Thickness Measurement

### c) Standard mode



## 2. Pre- and Post-CMP Defectivity Measurement Plan

- STI arrays of all dies are measured

